



10W,28V Plastic RF LDMOS Transistor

ITEH27010P3

Description

The ITEH27010P3 is a 10-watt, highly rugged, LDMOS transistor, designed for any general applications at frequencies up to 2.7GHz, in 6*5mm DFN plastic package, supporting surface mounted on PCB through high density grounding vias.

• Typical 1.8GHz Class AB RF Performance (On Innegration fixture with device soldered).

VDS=28V, IDQ=100mA Pulsed CW: 100 us width, 20% duty cycle.

Freq (MHz)	P1dB (dBm)	P1dB (W)	P1dB Eff (%)	P1dB Gain (dB)	P3dB (dBm)	P3dB (W)	P3dB Eff (%)
1810	40.78	12.0	58.3	20.26	41.53	14.2	60
1850	40.28	10.7	57.7	20.7	41.24	13.3	60
1880	39.83	9.6	56.4	20.32	41.04	12.7	60

• Typical 2.1GHz Class AB RF Performance (On Innegration fixture with device soldered).

VDS=28V, IDQ=100mA Pulsed CW: 100 us width, 20% duty cycle.

Freq (MHz)	P1dB (dBm)	P1dB (W)	P1dB Eff (%)	P1dB Gain (dB)	P3dB (dBm)	P3dB (W)	P3dB Eff (%)
2110	41.06	12.8	54.8	17.09	42	15.9	58.0
2140	40.58	11.4	56.7	17.04	41.54	14.3	59.1
2170	39.98	10.0	55.8	16.86	41	12.6	57.8

• Typical 2.6GHz Class AB RF Performance (On Innegration fixture with device soldered).

VDS=28V, IDQ=100mA Pulsed CW: 100 us width, 20% duty cycle.

Freq (MHz)	P1dB (dBm)	P1dB (W)	P1dB Eff (%)	P1dB Gain (dB)	P3dB (dBm)	P3dB (W)	P3dB Eff (%)
2600	41.13	12.97	52.00	15.87	41.99	15.80	54.53
2650	40.72	11.80	51.59	16.09	41.86	15.35	55.78
2700	40.39	10.95	50.50	15.61	41.63	14.55	54.90

• Typical UHF Class AB RF Performance (On Innegration fixture with device soldered).

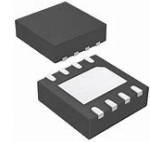
VDS=28V, IDQ=100mA Pulsed CW: 100 us width, 20% duty cycle.

Freq (MHz)	P1dB (dBm)	P1dB (W)	P1dB Eff (%)	P1dB Gain (dB)	P3dB (dBm)	P3dB (W)	P3dB Eff (%)
700	41.33	13.60	63.57	19.77	42.17	16.47	68.61
800	41.05	12.74	67.47	20.06	41.92	15.56	72.22
960	39.80	9.55	66.62	18.16	40.74	11.86	68.66

Note: High linear tuning result for each band upon request

Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Excellent thermal stability, low HCI drift
- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant





Suitable Applications

- Broadcast and Industrial, Scientific and Medical applications in the frequency range from HF to 2.7GHz
- All 4G/5G cellular application below 2.7GHz

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain--Source Voltage	V_{DS}	+65	Vdc
Gate--Source Voltage	V_{GS}	-10 to +10	Vdc
Operating Voltage	V_{DD}	+28	Vdc
Storage Temperature Range	T_{stg}	-65 to +150	°C
Case Operating Temperature	T_C	+150	°C
Operating Junction Temperature	T_J	+225	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case $T_C = 85^\circ\text{C}$, $P_{out} = 10\text{W}$ 2.1GHz	$R_{\theta JC}$	1.7	°C/W

Table 3. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JESD22--A114)	Class 2

Table 4. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
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DC Characteristics

Drain-Source Voltage $V_{GS} = 0$, $I_{DS} = 100\mu\text{A}$	$V_{(BR)DS}$		65		V
Zero Gate Voltage Drain Leakage Current ($V_{DS} = 28\text{V}$, $V_{GS} = 0\text{V}$)	I_{DSS}	—	—	1	μA
Gate--Source Leakage Current ($V_{GS} = 11\text{V}$, $V_{DS} = 0\text{V}$)	I_{GSS}	—	—	1	μA
Gate Threshold Voltage ($V_{DS} = 28\text{V}$, $I_D = 600\mu\text{A}$)	$V_{GS(th)}$	—	2	—	V
Gate Quiescent Voltage ($V_{DD} = 28\text{V}$, $I_D = 100\text{mA}$, Measured in Functional Test)	$V_{GS(Q)}$	—	2.8	—	V

Load Mismatch (In Innegration Test Fixture, 50 ohm system): $V_{DD} = 28\text{Vdc}$, $I_{DQ} = 100\text{mA}$, $f = 2100\text{MHz}$

VSWR 10:1 at 10W pulse CW Output Power	No Device Degradation
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Pin Configuration/Labeling and Description(Top view)



(EH10: Fixed labeling, YYWWZZ: Assembly batch code in specific year and week, changeable)

Pin No.	Symbol	Description
1,2,3,4	RF IN/VGS	Gate Bias/RF Input
5,6, 7,8	RF OUT /VDS	RF Output, Drain Bias
Backside metal	GND	DC/RF Ground. Must be soldered to EVB ground plane over array of vias for thermal and RF performance. Solder voids under Pkg Base will result in excessive junction temperatures causing permanent damage.

2500-2700MHz
Reference Circuit of Test Fixture Assembly Diagram
RO4350B 20mils

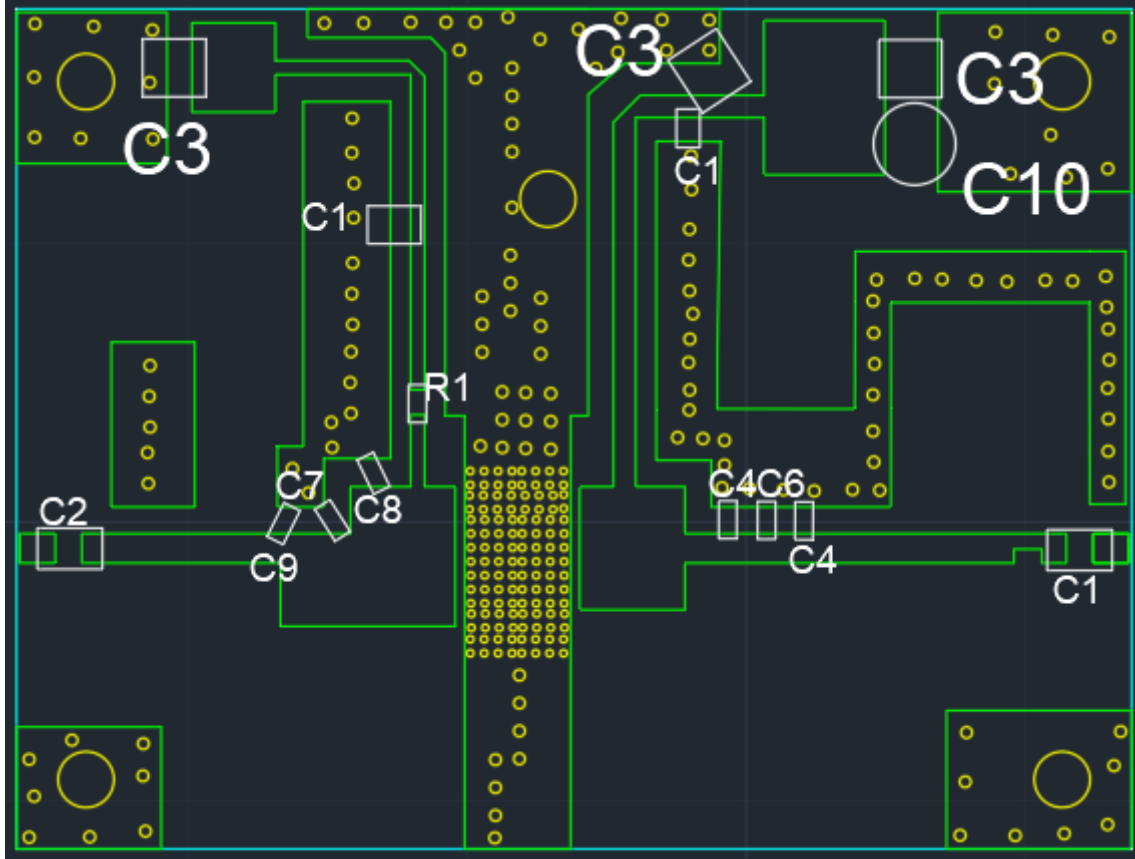


Figure 2. Test Circuit Component Layout

Table 4. Test Circuit Component Designations and Values

BOM		
Component	Value	Quantity
C2	3.9pF	1
C3	10uF/63V	3
R1	10 ohm	1
C1	12pF	3
C4	0.1pF	2
C10	470uF	1
C6	2.2 pF	1
C7	1.6pF	1
C8	2pF	1
C9	0.3pF	1



TYPICAL CHARACTERISTICS

Figure 3. Power Gain and Drain Efficiency as function of Power Out

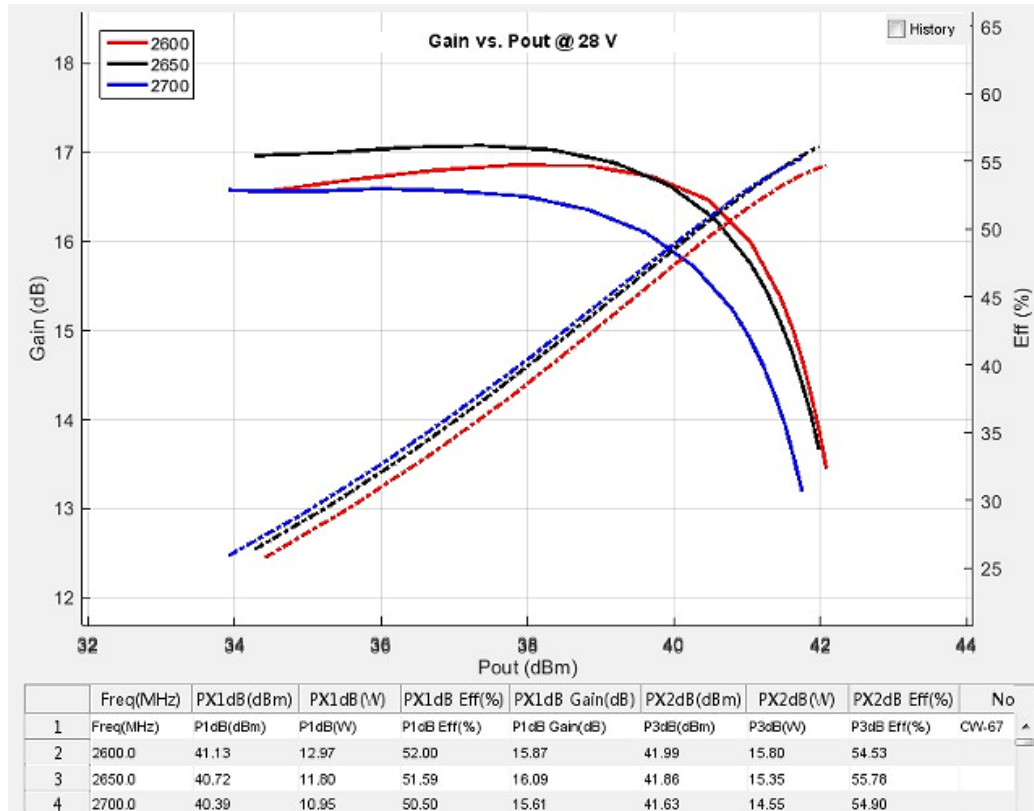
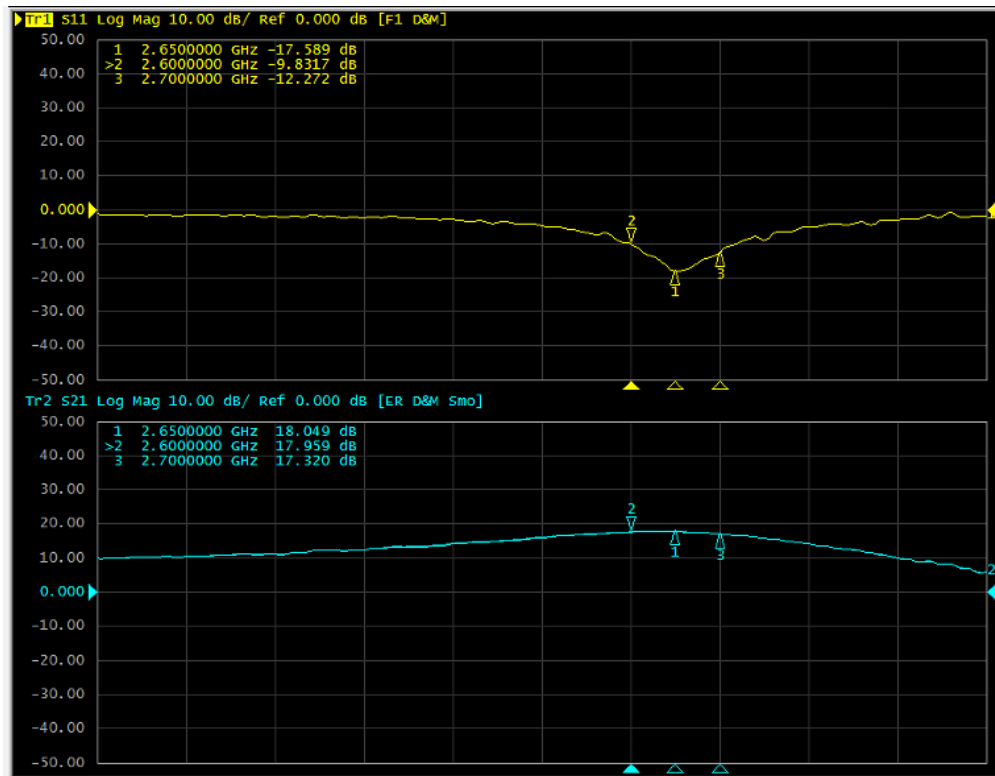


Figure 4. Network analyzer output S11/S21



2110-2170MHz
Reference Circuit of Test Fixture Assembly Diagram
RO4350B 20mils

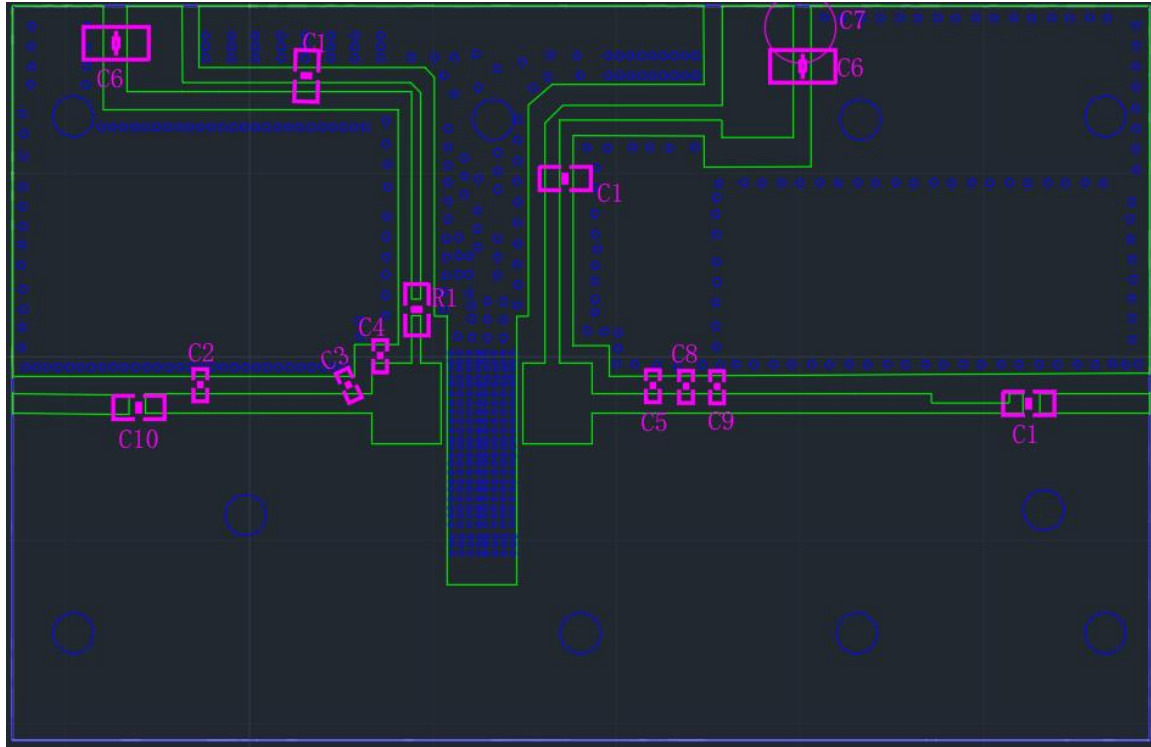


Figure 5. Test Circuit Component Layout

Table 5. Test Circuit Component Designations and Values

BOM		
Component	Value	Quantity
C2	1.2pF	1
C3	3.9pF	3
R1	10 ohm	1
C1	20pF	3
C4	2.4pF	1
C9	0.2 pF	1
C5	0.3 pF	1
C6	10uF/63V	1
C7	470uF	1
C8	2pF	1
C10	6.8pF	1

TYPICAL CHARACTERISTICS

Figure 6. Power Gain and Drain Efficiency as function of Power Out

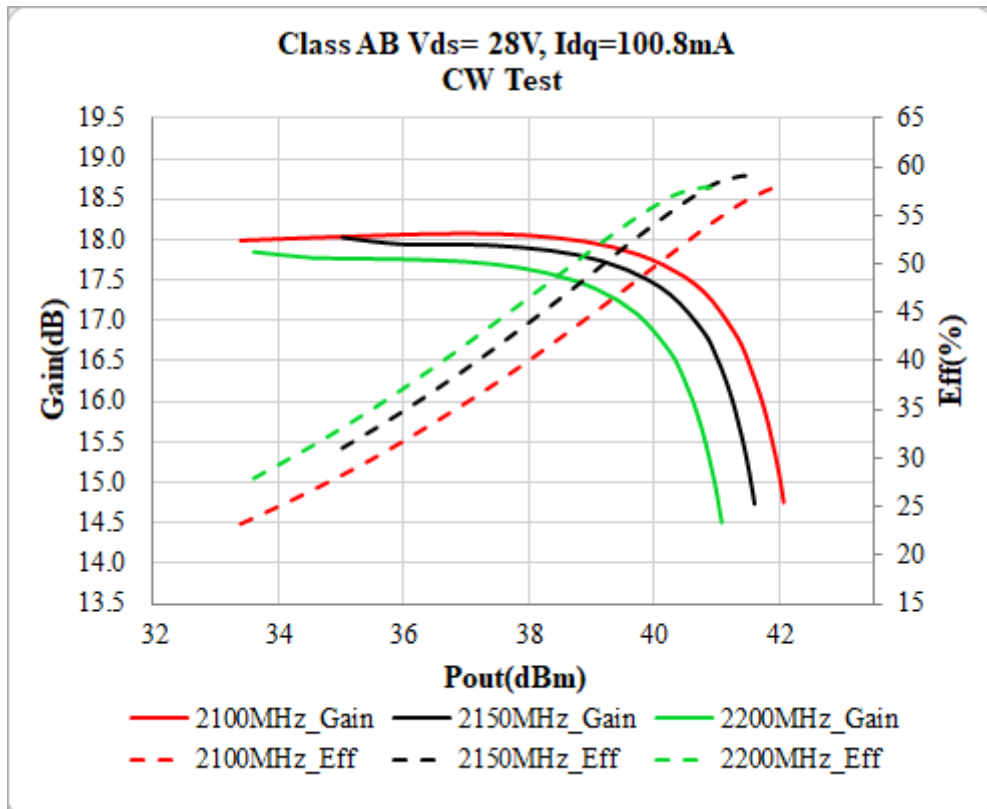
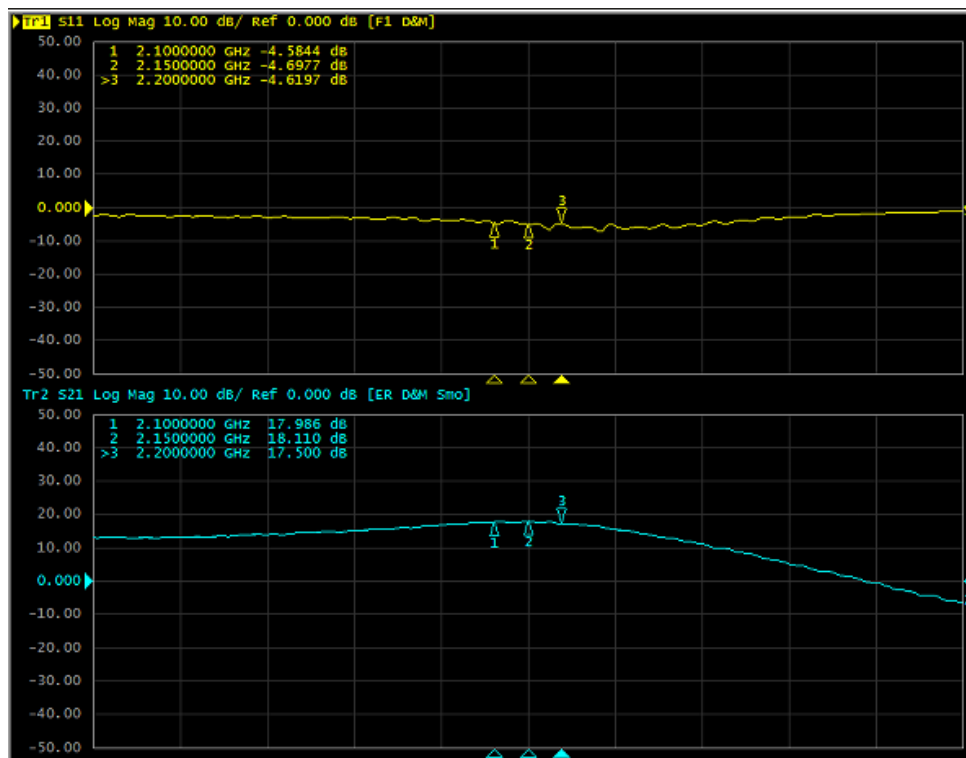


Figure 7. Network analyzer output S11/S21



1810-1880MHz
Reference Circuit of Test Fixture Assembly Diagram
RO4350B 20mils

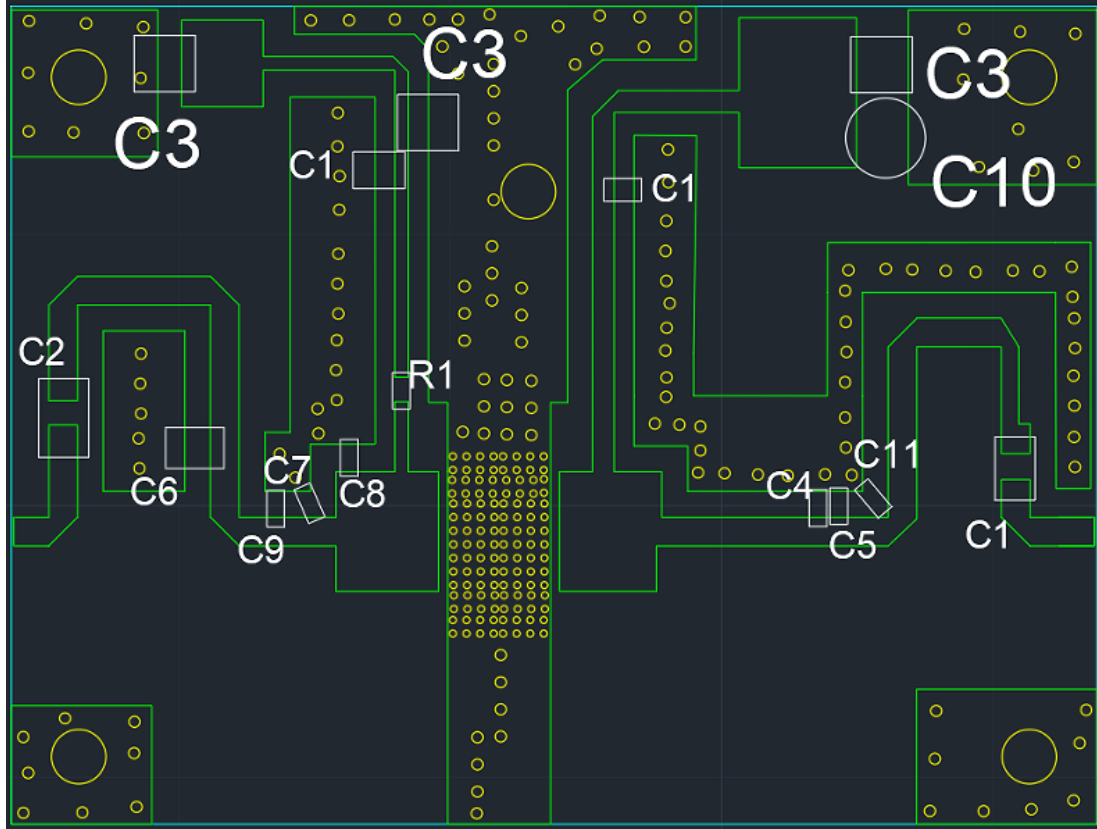


Figure 8. Test Circuit Component Layout

Table 6. Test Circuit Component Designations and Values

BOM		
Component	Value	Quantity
C2	3.9pF	1
C3	10uF/63V	3
R1	10 ohm	1
C1	20pF	3
C4	2.2pF	1
C10	470uF	1
C5	0.5 pF	1
C6	1 pF	1
C7	3.9pF	1
C8	2pF	1
C9	0.1pF	1
C11	1.1pF	1

TYPICAL CHARACTERISTICS

Figure 9. Power Gain and Drain Efficiency as function of Power Out

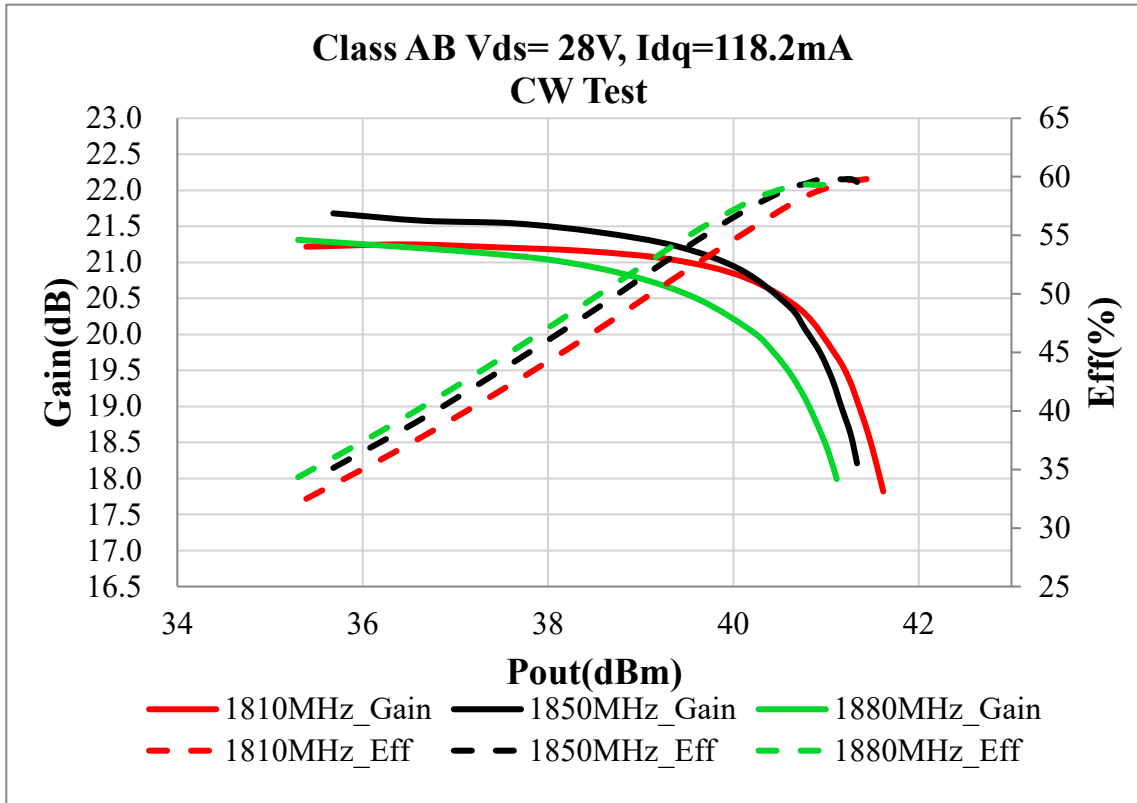
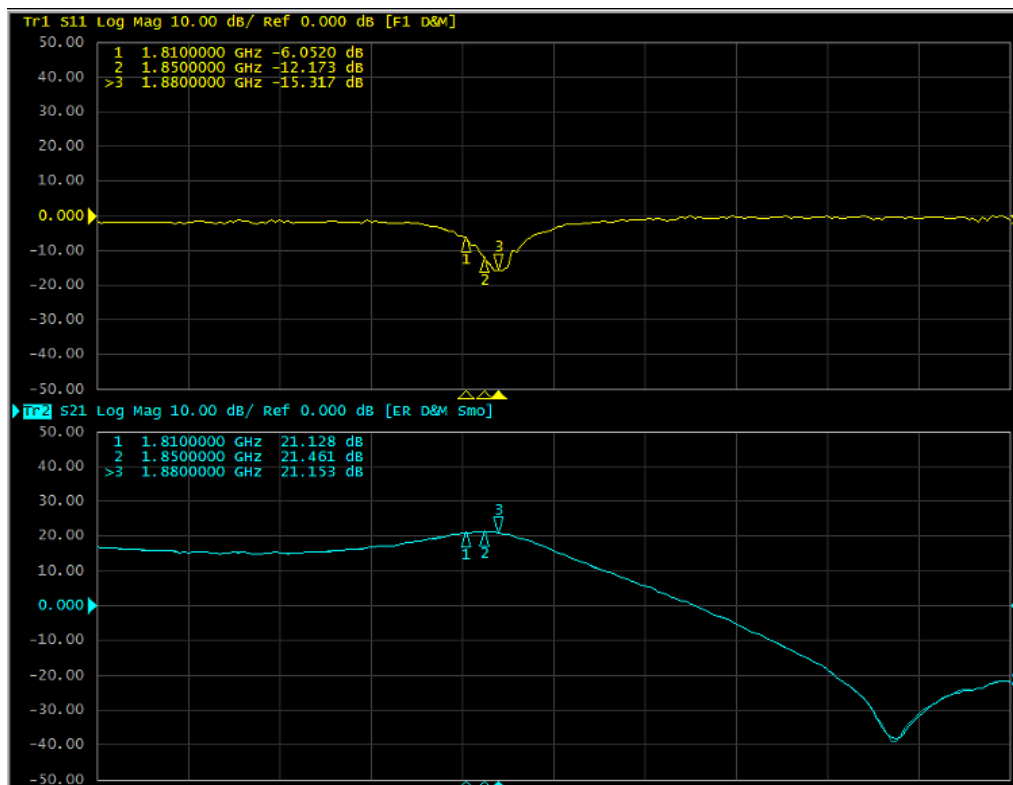


Figure 10. Network analyzer output S11/S21



700-960MHz
Reference Circuit of Test Fixture Assembly Diagram
RO4350B 20mils

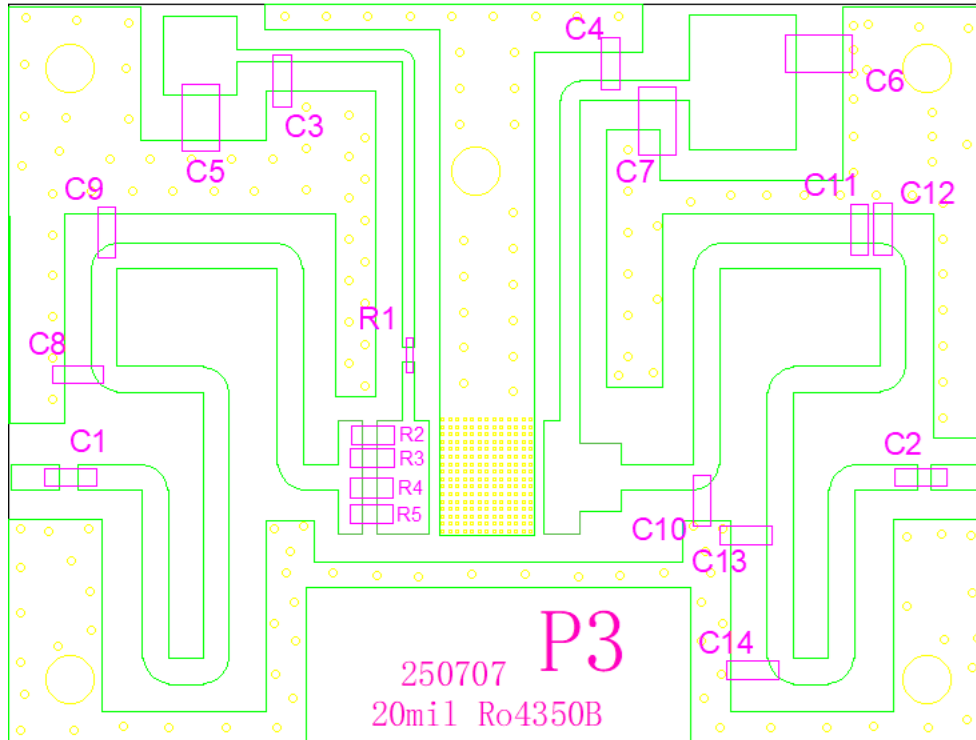


Figure 11. Test Circuit Component Layout

Table 6. Test Circuit Component Designations and Values

Part	Quantity	Description	Part Number	Manufacture
C1,C2,C3,C4	4	100pF High Q Capacitor	251SHS200BSE	TEMEX
C8	1	2.4pF High Q Capacitor	251SHS0R5BSE	TEMEX
C9	1	2.2pF High Q Capacitor	251SHS0R5BSE	TEMEX
C10	1	0.1pF High Q Capacitor	251SHS0R5BSE	TEMEX
C11	1	1.1pF High Q Capacitor	251SHS0R5BSE	TEMEX
C12	1	0.4pF High Q Capacitor	251SHS0R5BSE	TEMEX
C13	1	1.2pF High Q Capacitor	251SHS0R5BSE	TEMEX
C14	1	0.2pF High Q Capacitor	251SHS0R5BSE	TEMEX
C5,C6,C7	1	10uF MLCC	GRM32EC72A106ME05	Murata
R1,R2,R3,R4,R5	1	10 Ω Power Resistor	ESR03EZPF100	ROHM

TYPICAL CHARACTERISTICS

Figure 12. Power Gain and Drain Efficiency as function of Power Out

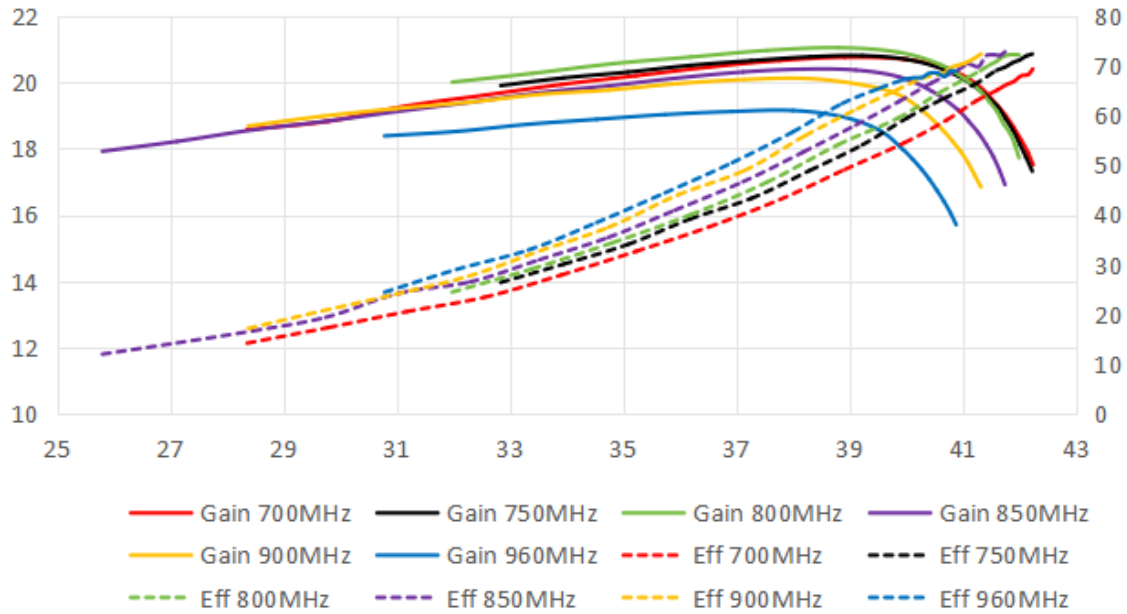
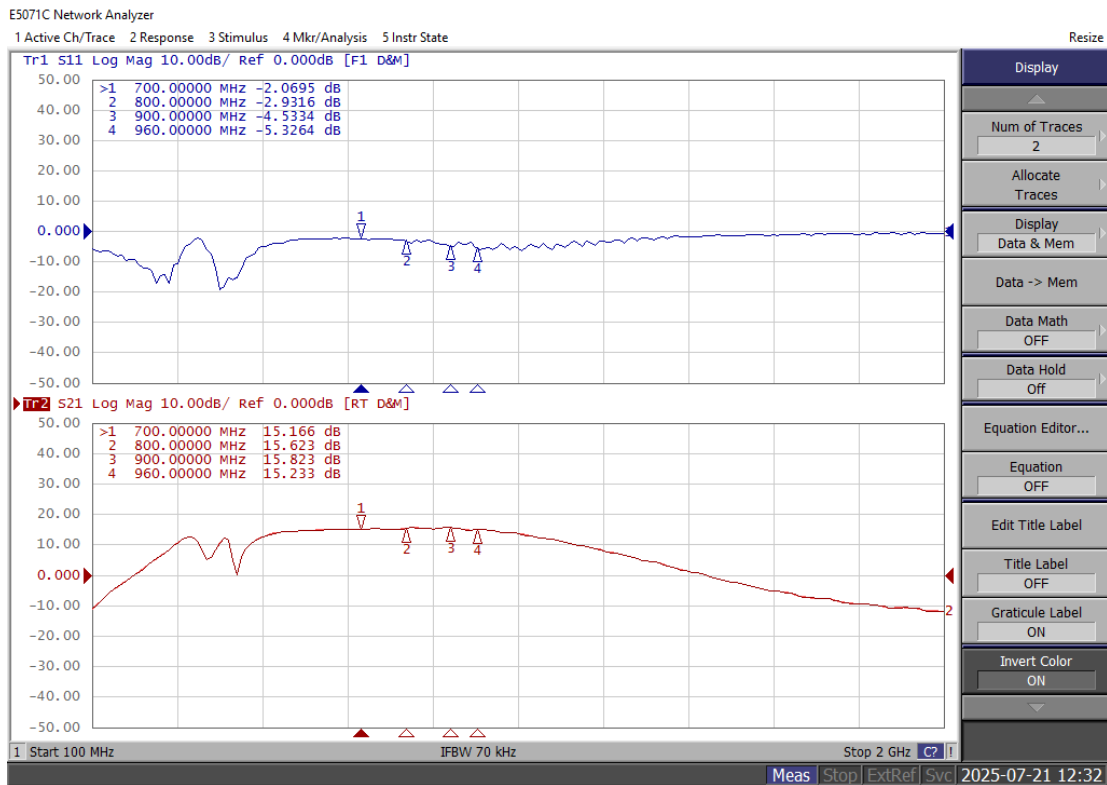


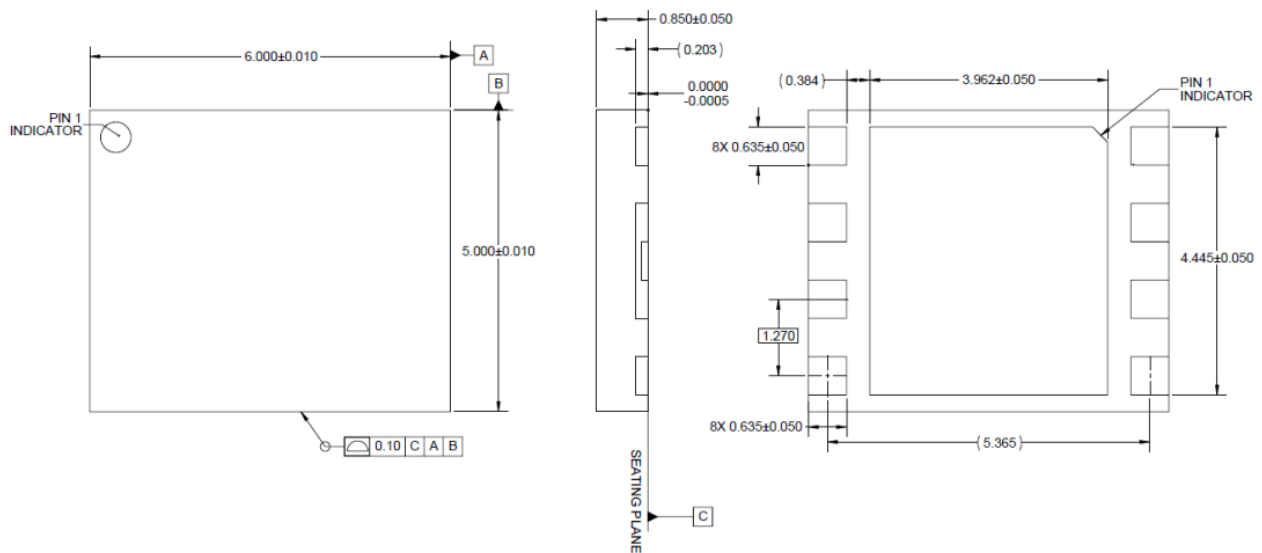
Figure 13. Network analyzer output S11/S21





Package

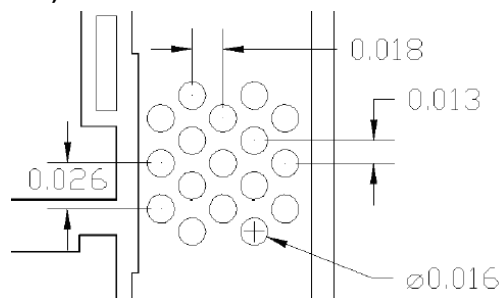
6*5 DFN Package



Notes:

1. All dimensions are in mm. Otherwise noted, the tolerance is ± 0.1 mm.
2. Package leads are gold plated.
3. Part is mold encapsulated.

Recommended vias layout: (all in inches)





Revision history

Table 7. Document revision history

Date	Revision	Datasheet Status
2023/12/14	Rev 1.0	Preliminary Datasheet
2025/5/26	Rev 1.1	Add the description of labeling
2025/7/21	Rev 1.2	Add 700-960MHz application data

Application data based on ZXY-23-16/17/18,HZH-25-04

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